



SHEET 1 OF 2

LIST OF ART CITED BY APPLICANT (PTO-1449)			ATTY. DOCKET NO. P-0601	APPLN. SERIAL NO. 10/733,515		
			APPLICANT(S) Choong-Jae LEE			
			FILING DATE December 12, 2003	GROUP 2615		
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
/PDI/	5,002,184	3/1991	LLOYD, Graham P.			
↓	5,689,824	11/1997	NAGAI, Michio			
	6,011,699	1/2000	MURRAY et al.			
U.S. PATENT APPLICATION PUBLICATIONS						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
/PD/	2004/0038703	2/2004	NOTO et al.			
↓	2005/0141187	6/2005	SHIMIZU, Masahito			
	2006/0110608	5/2006	AZUMI et al.			
U.S. PATENT APPLICATIONS						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PUBLICATION NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>
/PD/	1998-0057623	10/1998	Korea (Eng. Abstract and Full Korean Text)			X
↓	2001-0027039	4/2001	Korea (Eng. Abstract and Full Korean Text)			X
	2002-0066806	8/2002	Korea (Eng. Abstract and Full Korean Text)			X
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)						
Not in English.	Korean Office Action dated October 16, 2004					
	Korean Office Action dated October 21, 2004					
	Korean Office Action dated October 27, 2004					
EXAMINER	DATE CONSIDERED					
/Phylesha Dabney/	03/13/2007					

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



SHEET 2 OF 2

LIST OF ART CITED BY APPLICANT
(PTO-1449)

ATTY. DOCKET NO.
P-0601

APPLN. SERIAL NO.
10/733,515

APPLICANT(S)

Choong-Jae LEE

FILING DATE

December 12, 2003

GROUP

2615

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS

*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

U.S. PATENT APPLICATIONS

*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/PD/	JP 09-283950	10/1997	JAPAN (English Abstract and Japanese Full Text)			X	
	CN 2414554Y	1/2001	CHINA (English Abstract and Chinese Full Text)			X	
	CN 2447830Y	9/2001	CHINA (English Abstract and Chinese Full Text)			X	
↓	CN 1375976	10/2002	CHINA (English Abstract and Chinese Full Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

Chinese Office Action dated December 10, 2004

EXAMINER	/Phylesha Dabney/	DATE CONSIDERED	03/13/2007

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DYK:CLD/knh